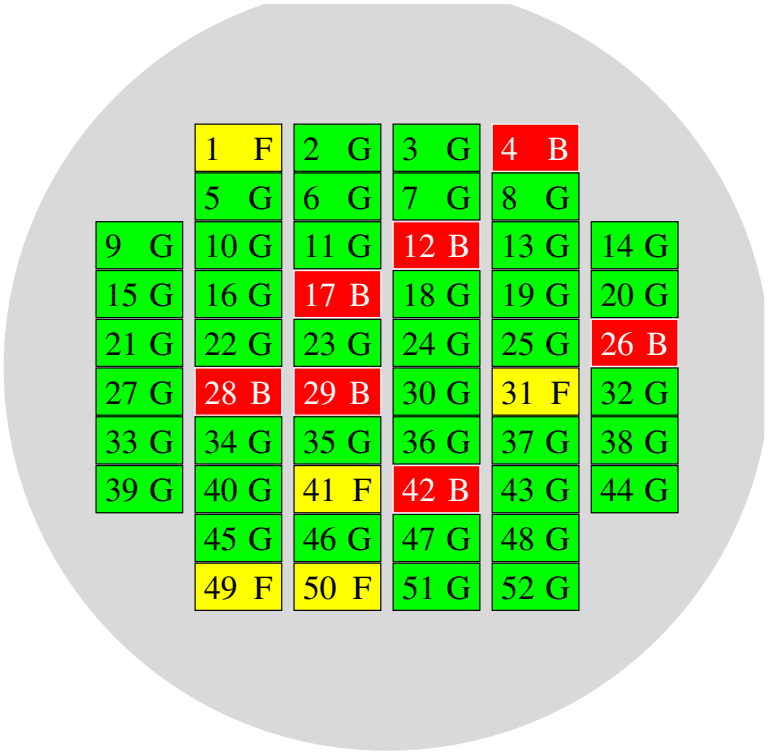
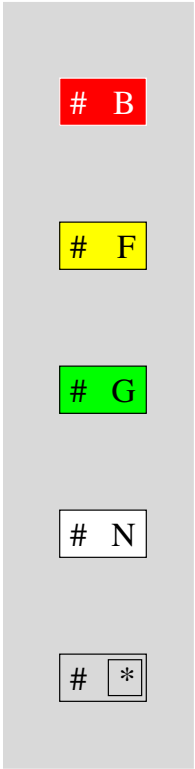
Die quality map for wafer 40 s/n: 21316-03-16

Date: 11/01/98





Bad die

Fair die

Good die

No info

Manually tagged